1 Characteristics

Symbol	Barameter	Value			Unit
Symbol	Falameter	Min.	Тур.	Max.	Unit
P _{IN}	Input power RFIN		10	13	dBm
V _{ESD}	ESD rating, human body model (JESD22-A114-C) all I/O one at a time while others connected to GND	2000			V
_	ESD rating, machine model, all I/O	200			
T _{OP}	Operating temperature range	-40		+85	°C

Table 1. Absolute maximum ratings (limiting values)

Table 2. Impedances (T_{amb} = 25 °C)

Symbol	Parameter		Value			
Symbol			Тур.	Max.	Unit	
Z _{DIFF}	Nominal differential impedance		matched to STLC2690		0	
Z _{SE}	Nominal single-ended impedance		50		52	

Table 3. RF performance (T_{amb} = 25 °C)

Symbol	Parameter	Test condition	Value			Unit	
Symbol	Farameter	Test condition	Min.	Тур.	Max.	Unit	
f	Frequency range (bandwidth)		2400		2500	MHz	
١L	Insertion loss in bandwidth			+1.2		dB	
R _{L_SE}	Return loss in bandwidth		15	21		dB	
ϕ_{imb}	Output phase imbalance (single ended)		-10		+10	o	
A _{imb}	Output amplitude imbalance		-1	0.5	1	dB	
CMRR	Common mode rejection (S _{SC12})		20			dB	
Att _{2fo}	2nd harmonic S21 attenuation	4800-5000 MHz	31			dB	
Att _{3f0}	3rd harmonic S21 attenuation	7200-7500 MHz	36				



1.1 Measurements









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Figure 9. Transmission (dB)



2 Package information

- Epoxy meets UL94, V0
- Lead-free package

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK[®] is an ST trademark.

2.1 Flip-Chip package information



Figure 10. Flip-Chip package outline

Table 4. Flip-Chip package mechanical data

Parameter	Description	Min.	Тур.	Max.	Unit
А	Bump height + substrate thickness	0.570	0.630	0.690	mm
A1	Bump height	0.155	0.205	0.255	mm
A2	Substrate thickness		0.400		mm
b	Bump diameter	0.215	0.255	0.295	mm
D	Y dimension of the die	1.590	1.640	1.690	mm
D1	Y pitch		0.660		mm
D2	Y pitch2		0.540		mm
E	X dimension of the die	0.890	0.940	0.990	mm
E1	X pitch		0.500		mm
fD	Distance from bump to edge of die on Y axis		0.225		mm
fE	Distance from bump to edge of die on X axis		0.215		mm
CCC				0.05	mm
\$			0.025		mm







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Note: More information is available in the STMicroelectronics application notes: AN2348 Flip-Chip: "Package description and recommendations for use"



3 Ordering information

Order code	Marking	Weight	Base Qty	Delivery mode
BALF-2690-02D3	SP	1.81 mg	5000	Tape and Reel

4 Revision history

Table 6. Document revision history	Table	6.	Document	revision	history
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Date	Revision	Changes
27-Sep-2013	1	Initial release
19-Dec-2013	2	Added product weight in Table 5 and updated Table 1.
19-Nov-2014	3	Added tape and reel dimensions.
02-Sep-2015	4	Updated <i>Figure 10</i> . Added <i>Figure 12</i> , <i>Figure 13</i> , <i>Figure 14</i> , <i>Figure 15</i> and <i>Table 4</i> .



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